

Complete if Known Substitute for form 1449A/PTO 10/731,089 Application Number INFORMATION DISCLOSURE December 10, 2003 Filing Date STATEMENT BY APPLICANT Shinya SASAGAWA et al. First Named Inventor (use as many sheets as necessary) 1765 Art Unit Not Assigned Yet Examiner Name Attorney Docket Number 1 of Sheet 740756-2676

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Examiner initials	Cite No.	U.S. Patent Document Number - Kind Code ² (if known)	Publication Date MM-DD-YYYY		une of Patentee or ant of Cited Document	Pages, Columns, Lines, W Relevant Passages or Rele Figures Appear	
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Examiner Signature		/Maki Angadi/		Considered	09/0	8/2006	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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INFORMATION DISCLOSURE	Application Number	10/731,089
STATEMENT BY APPLICANT	ETT. D.	December 10, 2003
	First Named Inventor	Shinya SASAGAWA et al.
(use as many sheets as necessary)	Art Unit	1765
	Examiner Name	
Sheet 1 of 1	Attorney Docket Number	740756-2676

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Examiner	/Maki Angadi/	Date	09/08/2006
Signature	/ Maki Migadi/	Considered	05,00,=000

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M. Wittmer et al., "Characteristics of TIN gate metal-oxide-semiconductor field effect transistors", J. Appl. Phys. Vol. 54, No. 3, March 1983, pp. 1423-1428.						

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Signature	/ Maki Migadi/	Considered	03/00/2000

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